

Please amend the present application as follows:

Claims

The following is a copy of Applicant's claims that identifies language being added with underlining ("___") and language being deleted with strikethrough ("——"), as is applicable:

1. (Currently amended) An optical alignment target formed on a substrate, the target comprising:

a planar central portion; and

a contoured contrasting region that surrounds the planar central portion, the contoured contrasting region being formed from a first layer deposited on the substrate, below a second layer deposited on the substrate the first layer, the second layer deposited below and a third layer deposited on the substrate the second layer, the first layer having the a topographic contour formed thereon that forms patterned surface irregularities on an upper surface of the first layer, the first layer at least partially projecting a patterned topographical contour through the second layer to the third layer the second and third layers each having a topographic contour that generally mirrors the topographic contour of the first layer as a result of the second and third layers having been deposited on the first layer such that upper surfaces of the second and third layers have contours that follow contours of the upper surface of the first layer;

wherein the optical alignment target can be readily detected from the contrast between the planar central portion and the contoured contrasting region that surrounds the planar central region.

2-3. (Canceled)

4. (Currently amended) The target as set forth in claim 1, wherein the ~~patterned topographical~~ topographic contours ~~includes~~ comprise sinusoidal contours that reflect light in a manner in which a plurality of alternating relatively brighter and relatively darker sections can be detected.

5-8. (Canceled)

9. (Currently amended) The target as set forth in claim 1, wherein the topographic ~~portion~~ contours ~~includes~~ comprise a plurality of indentations that are arranged in a grid pattern.

10. (Original) The target as set forth in claim 1, wherein the first layer is an electrical conductor, the second layer is an electrical insulator, and the third layer is an electrical conductor.

11. (Original) The target as set forth in claim 1, wherein the second layer includes an electrical conductor.

12. (Original) The target as set forth in claim 1, wherein electrical current flows through at least one of the first layer and the third layer.

13. (Original) The target as set forth in claim 1, wherein the substrate is segmented into at least one electrically functional portion and at least one electrically non-functional portion.

14. (Original) The target as set forth in claim 13, wherein the target is at least partially located on the electrically functional portion.

15. (Canceled)

16. (Original) The target as set forth in claim 1, wherein at least a portion of the third layer is recessed.

17. (Currently amended) The target as set forth in claim 1, wherein the ~~topography of two portions of an upper surface of the topographic portion~~ contours are at different vertical heights form repeated peaks and troughs.

18-19. (Canceled)

20. (Currently amended) The target as set forth in claim 1, wherein at least a ~~portion~~ one of the second and third layers ~~are~~ is transparent.

21. (Canceled)

22. (Currently amended) The target as set forth in claim 24 47, wherein the target is an orifice alignment target.

23. (Currently amended) A method of manufacture of a target, comprising:
depositing a first layer on a substrate;
forming a topographic ~~portion~~ contoured contrasting region on an upper surface of the first layer, the contoured contrasting region surrounding a planar central portion of the first layer and defining patterned surface irregularities; and

depositing a second layer on the ~~substrate~~ first layer, the second layer having a topographic contour in the contoured contrasting region that generally mirrors the topographic contour of the first layer as a result of the second layer having been deposited on the first layer, such that ~~wherein the topographic portion is projected through the second layer to form a patterned topographical contour on an~~ a portion of an upper surface of the second layer has contours that closely follow contours of the upper surface of the first layer, wherein the ~~patterned topographical contour acts as at least a portion of the target~~ can be readily detected from the contrast between the planar central portion and the contoured contrasting region that surrounds the planar central region.

24. (Currently amended) The method as set forth in claim 23, wherein the forming the first layer includes ~~patterning substantially in parallel strips, the parallel strips including~~ forming a sinusoidal pattern in the upper surface of the first layer that reflects light in a manner in which alternating strips of relatively bright light and relatively dark light appear when direct light is applied at the target.

25. (Canceled)

26. (Currently amended) The method as set forth in claim 23, wherein the forming the first layer includes forming indentations ~~formed in the first layer, the indentations that~~ are arranged in a grid pattern.

27-46. (Canceled)

47. (New) A target formed on a substrate comprising:

a first layer deposited below a second layer on the substrate, the second layer deposited below a third layer on the substrate, the first layer having the topographic contour formed thereon, the first layer at least partially projecting a patterned topographical contour through the second layer to the third layer;

a barrier layer disposed above the second layer; and

an orifice plate disposed above the barrier layer.